

## NEW X-RAY IMAGING CAMERA GIVES INSIGHT INTO X-RAY SOURCE CHARACTERISTICS

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Advances in microfocus x-ray sources and synchrotron beamlines have resulted in smaller, better defined x-ray beams. Characterizing such beams is an important and sometimes difficult task. In this paper, Rigaku will present results from a recently developed imaging camera allowing the characterization of x-ray imaging features on the order of microns. This new camera, the Xsight™ Micron, has been used to characterize the beam coming from a microfocus x-ray source with a new, high precision graded multilayer optic based on Rigaku's Arc)Sec™ technology. We will show the advantages of using a high-resolution imaging detector for the alignment of x-ray instruments, especially when using small, well defined beams. We will also show how this camera can help with synchrotron and other x-ray sources.